

Silicon Drift Detectors and fast readout electronics for high-rate, high-resolution X-ray measurements

Tuesday, 8 June 2021 14:00 (20 minutes)

Silicon Drift Detectors (SDDs) are widely used in X-ray measurements, in particular for spectroscopy applications. New challenges in terms of counting rates, for instance with new generations of synchrotron light sources, push the development towards new topologies of monolithic SDDs equipped with fast CMOS readout electronics. In this work, recent approaches taken by our team, namely ARDESIA and SCARLET projects, are illustrated together with example of detectors measurements already carried out at synchrotron facilities.

Primary author: FIORINI, Carlo Ettore (MI)

Presenter: FIORINI, Carlo Ettore (MI)

Session Classification: Session